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Substitute for form 1449A/PTO NFORMATION DISCLOSURE STATEMENT BY APPLICANT FEBRUATURATU (use as many sheets as necessary)

Complete if Known 09/678,266 **Application Number** Filing Date 10/3/2000 First Named Inventor Ming Xi Group Art Unit 1782 - 2827 Examiner Name u<u>nassigne</u>d Attorney Docket Number 4714P1/AMI-11

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Filing Late	10/3/2000
First Named Inventor	Ming Xi
Group Art Unit	1702 2823
Examiner Name	unassigned A PARNERE
Attorney Docket Number	4714D1/AMI 11

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First Named Inventor	Ming Xi
Group Art Unit	17627827
Examiner Name	Unassigned ZAMACE
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Application Number	09/678,266
Filing Date	10/03/2000
First Named Inventor	Ming Xi
Group Art Unit	4762 2-827
Examiner Name	Unassigned ZARNEKE
Attorney Docket Number	4714P1/AMI-11

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Application Number	unassigned 89/678266
Filing Date	Unassigned
First Named Inventor	Ming Xi
Group Art Unit	Unassigned 2827
Examiner Name	Unassigned ZARNEKE
Attorney Docket Number	4714 BA/AMI-00-11

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INFORM	ATION DISCLOSURE	Filing Date	10/3/2000
STATEM	ENT BY APPLICANT	First Named Inventor	Ming Xi
		Group Art Unit	1782 1827

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First Named Inventor	Ming Xi
Group Art Unit	Unassigned 2827
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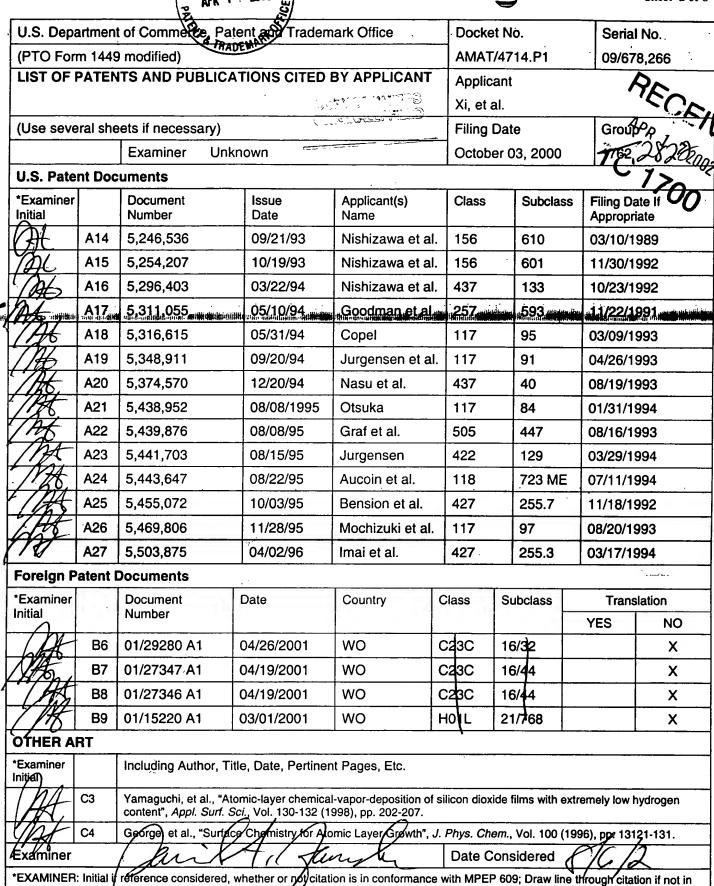
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